




# H11D1/H11D2/H11D3/H11D4

## Phototransistor, 5.3 KV, TRIOS®

### High $BV_{CER}$ Voltage Optocoupler

#### FEATURES

- CTR at  $I_F=10$  mA,  $BV_{CER}=10$  V:  $\geq 20\%$
- Good CTR Linearity with Forward Current
- Low CTR Degradation
- Very High Collector-Emitter Breakdown Voltage
  - H11D1/H11D2,  $BV_{CER}=300$  V
  - H11D3/H11D4,  $BV_{CER}=200$  V
- Isolation Test Voltage: 5300  $V_{RMS}$
- Low Coupling Capacitance
- High Common Mode Transient Immunity
- Phototransistor Optocoupler in 6 Pin DIP Package with Base Connection
- Field Effect Stable: TRIOS\*
-  VDE 0884 Available with Option 1
- Underwriters Lab File #E52744

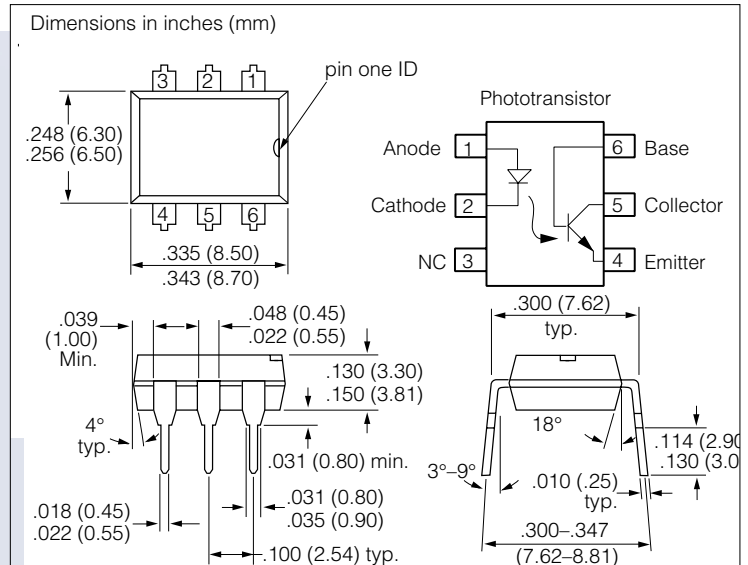
#### APPLICATIONS

- Telecommunications
- Replace Relays

#### DESCRIPTION

The H11D1/2/3 are optocouplers with very high  $BV_{CER}$ . They are intended for telecommunications applications or any DC application requiring a high blocking voltage.

\*TRIOS—TRansparent IO Shield



#### Maximum Ratings $T_A=25^\circ\text{C}$

##### Emitter

Reverse Voltage	6.0 V
DC Forward Current	60 mA
Surge Forward Current ( $t_p \leq 10 \mu\text{s}$ )	2.5 A
Total Power Dissipation	100 mW

##### Detector

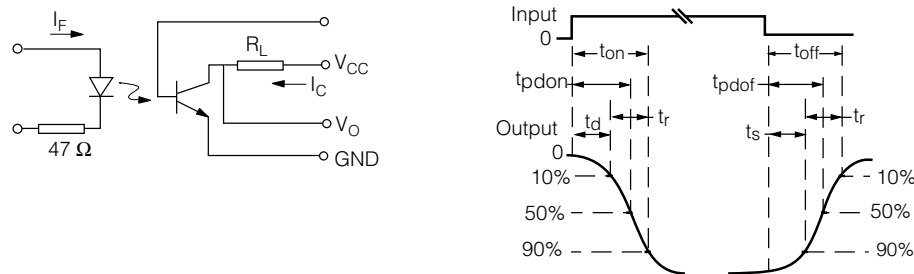
Collector-Emitter Voltage	
H11D1/2	300 V
H11D3 /4	200 V
Collector-Base Voltage	
H11D1/2	300 V
H11D3 /4	200 V
Emitter-Base Voltage	7.0 V
Collector Current	100 mA
Total Power Dissipation	300 mW

##### Package

Isolation Test Voltage (between emitter and detector, refer to climate DIN 50014, part 2, Nov. 74)	5300 $V_{RMS}$
Insulation Thickness between Emitter and Detector	$\geq 0.4$ mm
Creepage Distance	$\geq 7.0$ mm
Clearance Distance	$\geq 7.0$ mm
Comparative Tracking Index (per DIN IEC 112/VDE 0303, part 1)	175
Isolation Resistance	
$V_{IO}=500$ V, $T_A=25^\circ\text{C}$	$\geq 10^{12} \Omega$
$V_{IO}=500$ V, $T_A=100^\circ\text{C}$	$\geq 10^{11} \Omega$
Storage Temperature Range	$-55^\circ\text{C}$ to $+150^\circ\text{C}$
Operating Temperature Range	$-55^\circ\text{C}$ to $+100^\circ\text{C}$
Junction Temperature	$100^\circ\text{C}$
Soldering Temperature (max. 10 sec., dip soldering: distance to seating plane $\geq 1.5$ mm)	$260^\circ\text{C}$

**Characteristics**  $T_A=25^\circ\text{C}$ , unless otherwise specified)

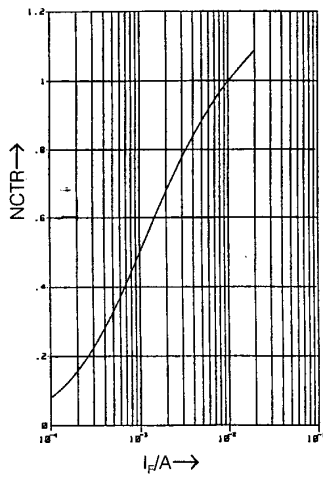
Parameter	Symbol	Min	Typ	Max	Unit	Condition	
<b>Emitter</b>							
Forward Voltage	$V_F$	—	1.1	1.5	V	$I_F=10\text{ mA}$	
Reverse Voltage	$V_R$	6.0	—	—		$I_R=10\text{ }\mu\text{A}$	
Reverse Current	$I_R$	—	0.01	10	$\mu\text{A}$	$V_R=6.0\text{ V}$	
Capacitance	$C_O$	—	25	—	pF	$V_R=0\text{ V}$ , $f=1.0\text{ MHz}$	
Thermal Resistance	$R_{thJA}$	—	750	—	K/W	—	
<b>Detector</b>							
Voltage, Collector-Emitter	H11D1/H11D2	$BV_{CER}$	300	—	—	V	$I_{CE}=1.0\text{ mA}$ , $R_{BE}=1.0\text{ M}\Omega$
	H11D3/H11D4		200	—	—	—	—
Voltage, Emitter-Base		$BV_{EBO}$	7.0	—	—	—	$I_{EB}=100\text{ }\mu\text{A}$
Capacitance		$C_{CE}$	—	7.0	—	pF	$V_{CE}=10\text{ V}$ , $f=1.0\text{ MHz}$
		$C_{CB}$	—	8.0	—	pF	$V_{CB}=10\text{ V}$ , $f=1.0\text{ MHz}$
		$C_{EB}$	—	38	—	pF	$V_{EB}=5.0\text{ V}$ , $f=1.0\text{ MHz}$
Thermal Resistance		$R_{thJA}$	—	250	—	K/W	—
<b>Package</b>							
Coupling Capacitance		$C_C$	—	0.6	—	pF	—
Coupling Transfer Ratio		$I_C/I_F$	20	—	—	%	$I_F=10\text{ mA}$ , $V_{CE}=10\text{ V}$ , $R_{BE}=1.0\text{ M}\Omega$
Collector-Emitter, Saturation Voltage		$V_{CEsat}$	—	0.25	0.4	V	$I_F=10\text{ mA}$ , $I_C=0.5\text{ mA}$ , $R_{BE}=1.0\text{ M}\Omega$
Leakage Current, Collector-Emitter	H11D1/H11D2	$I_{CER}$	—	—	100	nA	$V_{CE}=200\text{ V}$ , $R_{BE}=1.0\text{ M}\Omega$
	H11D3/H11D4		—	—	—	—	$V_{CE}=100\text{ V}$ , $R_{BE}=1.0\text{ M}\Omega$
	H11D1/H11D2		—	—	250	$\mu\text{A}$	$V_{CE}=300\text{ V}$ , $R_{BE}=1.0\text{ M}\Omega$ , $T_A=100^\circ\text{C}$
	H11D3/H11D4		—	—	—	—	$V_{CE}=100\text{ V}$ , $R_{BE}=1.0\text{ M}\Omega$ , $T_A=100^\circ\text{C}$

**Figure 1. Switching times measurement-test circuit and waveforms****Switching Times (typ.)**

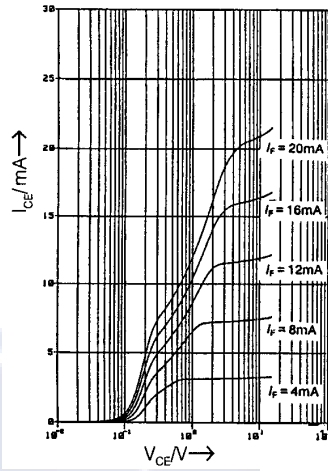
$I_C=2.0\text{ mA}$  (to be adjusted by varying  $I_F$ ),  $R_L=100\Omega$ ,  
 $T_A=25^\circ\text{C}$ ,  $V_{CC}=10\text{ V}$

Description	Symbol	Values	Unit
Turn-On Time	$t_{ON}$	5.0	$\mu\text{s}$
Rise Time	$t_r$	2.5	
Turn-Off Time	$t_{OFF}$	6.0	
Fall Time	$t_f$	5.5	

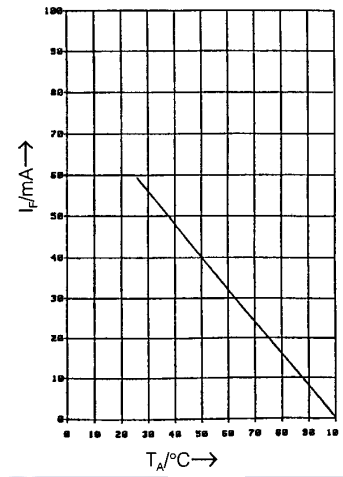
**Figure 2. Current transfer ratio (typ.)**  $V_{CE}=10\text{ V}$ ,  $T_A=25^\circ\text{C}$ , normalized to  $I_F=10\text{ mA}$ ,  $\text{NCTR}=f(I_F)$



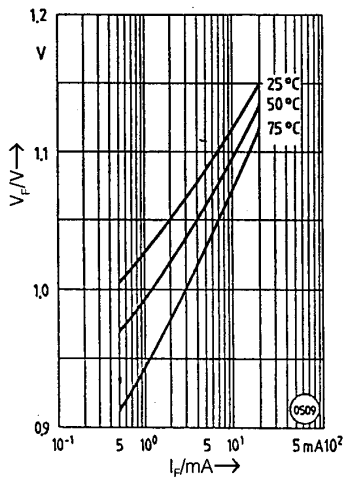
**Figure 5. Output characteristics (typ.)**  $T_A=25^\circ\text{C}$ ,  $I_{CE}=f(V_{CE}, I_F)$



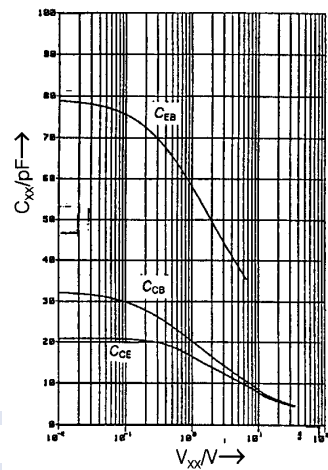
**Figure 8. Permissible loss diode**  $I_F=f(T_A)$



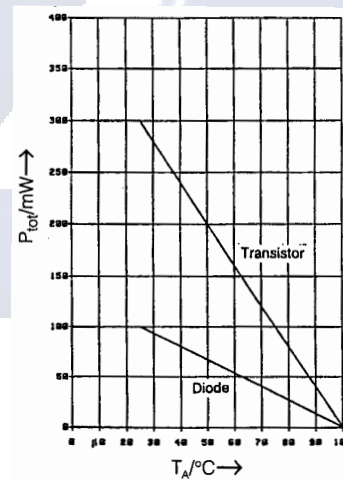
**Figure 3. Diode forward voltage (typ.)**  $V_F=f(I_F, T_A)$



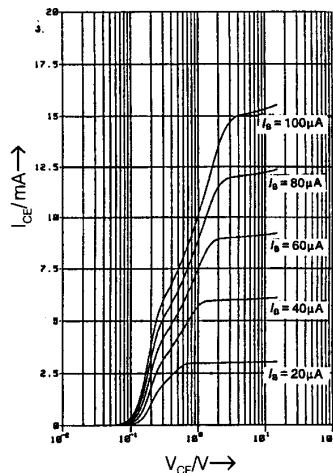
**Figure 6. Transistor capacitances (typ.)**  $T_A=25^\circ\text{C}$ ,  $f=1.0\text{ MHz}$ ,  $C_{CE}=f(V_{CE})$ ,  $C_{CB}=f(V_{CB})$ ,  $C_{EB}=f(V_{EB})$



**Figure 9. Permissible power dissipation**  $P_{tot}=f(T_A)$



**Figure 4. Output characteristics (typ.)**  $T_A=25^\circ\text{C}$ ,  $I_{CE}=f(V_{CE}, I_B)$



**Figure 7. Collector-emitter leakage current (typ.)**  $I_F=0$ ,  $R_{BE}=1.0\text{ M}\Omega$ ,  $I_{CER}=f(V_{CE})$

